3	<i>iea</i>	rc	:h	No	ote	S	
	Ш	Ш			Ш		

lotes	Application/Control No.	Applicant(s)/Patent under Reexamination DIAB ET AL.		
	09/195,791			
	Examiner	Art Unit		
	Eric F. Winakur	3736		

SEARCHED				
Class	Subclass	Date	Examiner	
600	310, 322, 323, 330, 336, 473	10/26/2003	EFW	
600	476	10/26/2003	EFW	
356	041	10/26/2003	EFW	
UPDATED	above	9/14/2005	EFW	
	•	~		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
	,				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
	,		